

# Notice of Allowability

Application No.

09/873,447

Examiner

Pamela E. Perkins

Applicant(s)

YAMAZAKI ET AL.

Art Unit

2822

## -- The MAILING DATE of this communication appears on the cover sheet with the correspondence address--

All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. **THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS.** This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.

1. ☒ This communication is responsive to the filing of the RCE on 29 November 2005.
2. ☒ The allowed claim(s) is/are 43-123.
3. ☒ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
  - a) ☒ All b) ☐ Some\* c) ☐ None of the:
    1. ☒ Certified copies of the priority documents have been received.
    2. ☐ Certified copies of the priority documents have been received in Application No. \_\_\_\_\_.
    3. ☐ Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).

\* Certified copies not received: \_\_\_\_\_.

Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.

**THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.**

4. ☐ A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.
  5. ☐ CORRECTED DRAWINGS ( as "replacement sheets") must be submitted.
    - (a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review ( PTO-948) attached
      - 1) ☐ hereto or 2) ☐ to Paper No./Mail Date \_\_\_\_\_.
    - (b) ☐ including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date \_\_\_\_\_.
- Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).
6. ☐ DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.

## Attachment(s)

1. ☐ Notice of References Cited (PTO-892)
2. ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/08), Paper No./Mail Date \_\_\_\_\_
4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material
5. ☐ Notice of Informal Patent Application (PTO-152)
6. ☐ Interview Summary (PTO-413), Paper No./Mail Date \_\_\_\_\_
7. ☐ Examiner's Amendment/Comment
8. ☒ Examiner's Statement of Reasons for Allowance
9. ☐ Other \_\_\_\_\_.

### **DETAILED ACTION**

This office action is in response to the filing of the RCE on 29 November 2005.

Claims 43-123 are pending.

### ***Allowable Subject Matter***

Claims 43-123 are allowed.

### ***Reasons for Allowance***

The following is an examiner's statement of reasons for allowance: referring to independent claims 43, 44, 53, 54, 73-75, 94, 95, 104 and 105, prior art does not anticipate, teach, or suggest making a plurality of thin film transistors in an on state, measuring a value of electric current flowing in said measurement wiring, and judging whether or not the plurality of thin film transistors are defective from the value; and forming a plurality of pixel electrodes by patterning a conductive film after the judging.

Referring to independent claims 47, 48, 55, 56, 82, 83-85, 106 and 107, prior art does not anticipate, teach, or suggest forming an inspection conductive film electrically connected to all of a plurality of pixel electrodes electrically connected to a plurality of thin film transistors respectively, measuring a value of electric current flowing in a measurement wiring, and judging whether or not the plurality of thin film transistors and the plurality of pixel electrodes are defective from the value; and removing the inspection conductive film.

For example, Zhang et al. (6,472,256) disclose a method of manufacturing a display panel for an active matrix type device where an interlayer insulating film is formed to cover a plurality of thin film transistors provided on an insulating surface; forming contact holes in the interlayer insulating film; forming a plurality of connecting wirings respectively connected to source regions or drain regions of the thin film transistors through the contact holes; forming a conductive film; making the plurality of thin film transistors in an on state, wherein an on state is defined by a predetermined electric potential is applied to one of a source region and a drain region of a TFT, the state of the TFT is defined as being on if a desired potential can be applied to the other; and forming a plurality of pixel electrodes by patterning the conductive film to be electrically connected to the plurality of thin film transistors, respectively.

However, Zhang et al. do not disclose, anticipate, teach, or suggest forming a measurement wiring in contact with the insulating surface, measuring a value of electric current flowing in the measurement wiring, and judging whether or not the plurality of thin film transistors are defective from the value prior to forming a plurality of pixel electrodes and forming an inspection conductive film electrically connected to all of a plurality of pixel electrodes electrically connected to a plurality of thin film transistors respectively, measuring a value of electric current flowing in a measurement wiring, and judging whether or not the plurality of thin film transistors and the plurality of pixel electrodes are defective from the value; and removing the inspection conductive film

Kawaguchi et al. (4,940,934) disclose a method of manufacturing a display panel where a plurality of thin film transistors is connected to a measurement wiring;

measuring a value of electric current flowing in the measurement wiring, and judging whether or not the plurality of thin film transistors are defective from the value; and forming a plurality of pixel electrodes to be electrically connected to the plurality of thin film transistors.

However, Kawaguchi et al. do not disclose, anticipate, teach or suggest making a plurality of thin film transistors in an on state, measuring a value of electric current flowing in said measurement wiring, and judging whether or not the plurality of thin film transistors are defective from the value; and forming a plurality of pixel electrodes by patterning a conductive film after the judging and forming an inspection conductive film electrically connected to all of a plurality of pixel electrodes electrically connected to a plurality of thin film transistors respectively, measuring a value of electric current flowing in a measurement wiring, and judging whether or not the plurality of thin film transistors and the plurality of pixel electrodes are defective from the value; and removing the inspection conductive film.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

### ***Conclusion***

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Pamela E. Perkins whose telephone number is (571)


Art Unit: 2822

272-1840. The examiner can normally be reached on Monday thru Friday, 8:30am to 5:00pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Zandra Smith can be reached on (571) 272-2429. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

PEP

  
ZANDRA V. SMITH  
PRIMARY EXAMINER  
12/5/05